

Notice of References Cited	Application/Control No. 10/646,817	Applicant(s)/Patent Under Reexamination YOON ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,921,095	07-1999	Lee et al.	62/175
	B	US-6,412,286	07-2002	Park et al.	62/3.6
	C	US-5,722,244	03-1998	Shelton, Norman L.	62/74
	D	US-4,795,088	01-1989	Kobayashi et al.	236/49.3
	E	US-5,910,163	06-1999	Schlamp, Hans	62/256
	F	US-5,816,068	10-1998	Oh et al.	62/407
	G	US-4,895,001	01-1990	Jondahl, Joseph S.	62/326
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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